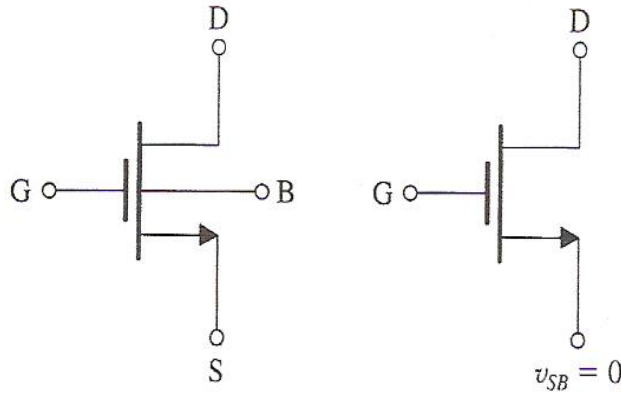


TABLE 4.1 Summary of the MOSFET Current-Voltage Characteristics

NMOS Transistor

Symbol:



Overdrive voltage:

$$v_{OV} = v_{GS} - V_t$$

$$v_{GS} = V_t + v_{OV}$$

Operation in the *triode* region:

■ Conditions:

$$(1) \ v_{GS} \geq V_t \Leftrightarrow v_{OV} \geq 0$$

$$(2) \ v_{GD} \geq V_t \Leftrightarrow v_{DS} \leq v_{GS} - V_t \Leftrightarrow v_{DS} \leq v_{OV}$$

■ *i-v* Characteristics:

$$i_D = \mu_n C_{ox} \frac{W}{L} \left[(v_{GS} - V_t) v_{DS} - \frac{1}{2} v_{DS}^2 \right]$$

■ For $v_{DS} \ll 2(v_{GS} - V_t) \Leftrightarrow v_{DS} \ll 2v_{OV}$

$$r_{DS} \equiv \frac{v_{DS}}{i_D} = 1 / \left[\mu_n C_{ox} \frac{W}{L} (v_{GS} - V_t) \right]$$

Operation in the *saturation* region:

■ Conditions:

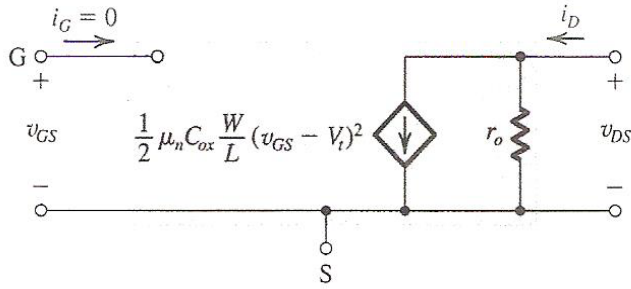
$$(1) \ v_{GS} \geq V_t \Leftrightarrow v_{OV} \geq 0$$

$$(2) \ v_{GD} \leq V_t \Leftrightarrow v_{DS} \geq v_{GS} - V_t \Leftrightarrow v_{DS} \geq v_{OV}$$

■ *i-v* Characteristics:

$$i_D = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (v_{GS} - V_t)^2 (1 + \lambda v_{DS})$$

■ Large-signal equivalent circuit model:



$$r_o = \left[\lambda \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_t)^2 \right]^{-1} = \frac{V_A}{I_D}$$

where

$$I_D = \frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_t)^2$$

Threshold voltage:

$$V_t = V_{t0} + \gamma (\sqrt{2\phi_f + |V_{SB}|} - \sqrt{2\phi_f})$$

Process parameters:

$$C_{ox} = \epsilon_{ox} / t_{ox} \quad (\text{F/m}^2)$$

$$k'_n = \mu_n C_{ox} \quad (\text{A/V}^2)$$

$$V'_A = (V_A / L) \quad (\text{V/m})$$

$$\lambda = (1 / V_A) \quad (\text{V}^{-1})$$

$$\gamma = \sqrt{2qN_A \epsilon_s} / C_{ox} \quad (\text{V}^{1/2})$$

Constants:

$$\epsilon_0 = 8.854 \times 10^{-12} \text{ F/m}$$

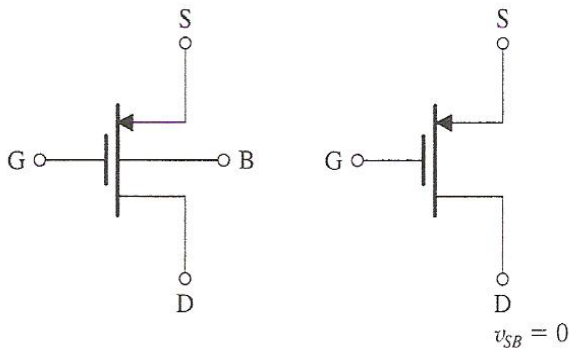
$$\epsilon_{ox} = 3.9 \epsilon_0 = 3.45 \times 10^{-11} \text{ F/m}$$

$$\epsilon_s = 11.7 \epsilon_0 = 1.04 \times 10^{-10} \text{ F/m}$$

$$q = 1.602 \times 10^{-19} \text{ C}$$

PMOS Transistor

Symbol:



Overdrive voltage:

$$v_{OV} = v_{GS} - V_t$$

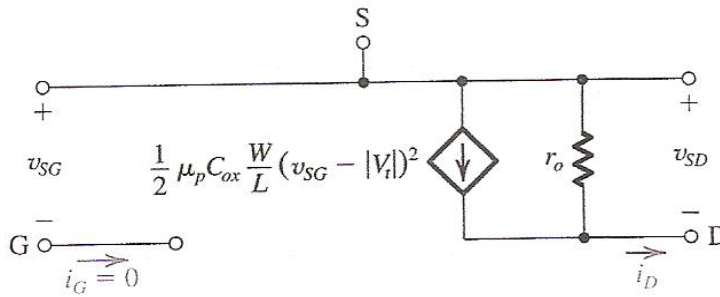
$$v_{SG} = |V_t| + |v_{OV}|$$

TABLE 4.1 (Continued)

***i-v* Characteristics:**

Same relationships as for NMOS transistors except:

- Replace μ_n , k'_n , and N_A with μ_p , k'_p , and N_D , respectively.
- V_t , V_{t0} , V_A , λ , and γ are negative.
- Conditions for operation in the **triode** region:
 - (1) $v_{GS} \leq V_t \Leftrightarrow v_{OV} \leq 0 \Leftrightarrow v_{SG} \geq |V_t|$
 - (2) $v_{DG} \geq |V_t| \Leftrightarrow v_{DS} \geq v_{GS} - V_t \Leftrightarrow v_{SD} \leq |v_{OV}|$
- Conditions for operation in the **saturation** region:
 - (1) $v_{GS} \leq V_t \Leftrightarrow v_{OV} \leq 0 \Leftrightarrow v_{SG} \geq |V_t|$
 - (2) $v_{DG} \leq |V_t| \Leftrightarrow v_{DS} \leq v_{GS} - V_t \Leftrightarrow v_{SD} \geq |v_{OV}|$
- Large-signal equivalent circuit model:



$$r_o = \left[|\lambda| \frac{1}{2} \mu_p C_{ox} \frac{W}{L} (V_{SG} - |V_t|)^2 \right]^{-1} = \frac{|V_A|}{I_D}$$

where

$$I_D = \frac{1}{2} \mu_p C_{ox} \frac{W}{L} (V_{SG} - |V_t|)^2$$

TABLE 4.2 Small-Signal Equivalent-Circuit Models for the MOSFET

Small-Signal Parameters

NMOS transistors:

■ Transconductance:

$$g_m = \mu_n C_{ox} \frac{W}{L} V_{OV} = \sqrt{2\mu_n C_{ox} \frac{W}{L} I_D} = \frac{2I_D}{V_{OV}}$$

■ Output resistance:

$$r_o = V_A / I_D = 1 / \lambda I_D$$

■ Body transconductance:

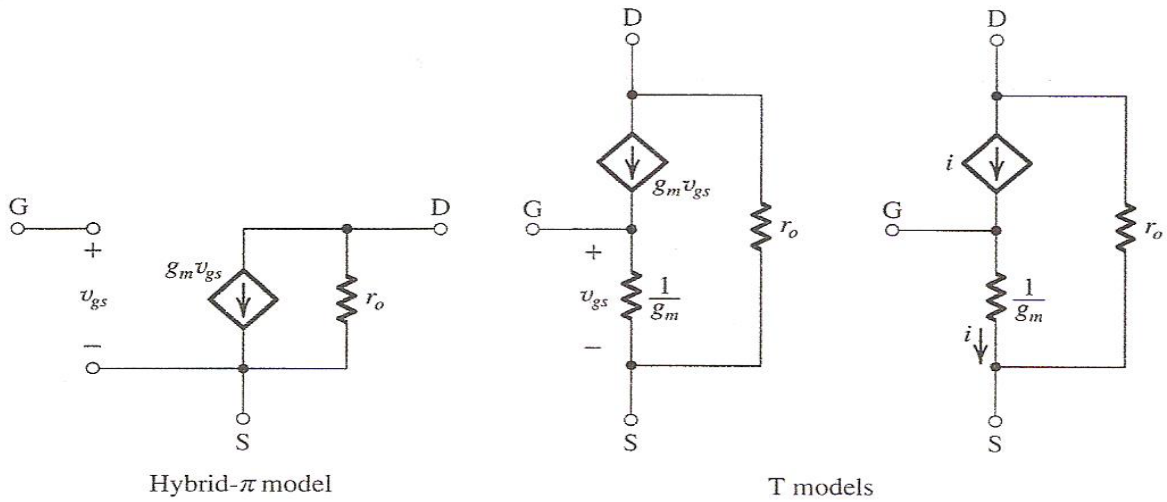
$$g_{mb} = \chi g_m = \frac{\gamma}{2\sqrt{2\phi_f + V_{SB}}} g_m$$

PMOS transistors:

Same formulas as for NMOS *except* using $|V_{OV}|$, $|V_A|$, $|\lambda|$, $|\gamma|$, $|V_{SB}|$, and $|\chi|$ and replacing μ_n with μ_p .

TABLE 4.2 (Continued)

Small-Signal Equivalent Circuit Models when $|V_{SB}| = 0$ (i.e., No Body Effect)



Small-Signal Circuit Model when $|V_{SB}| \neq 0$ (i.e., Including the Body Effect)

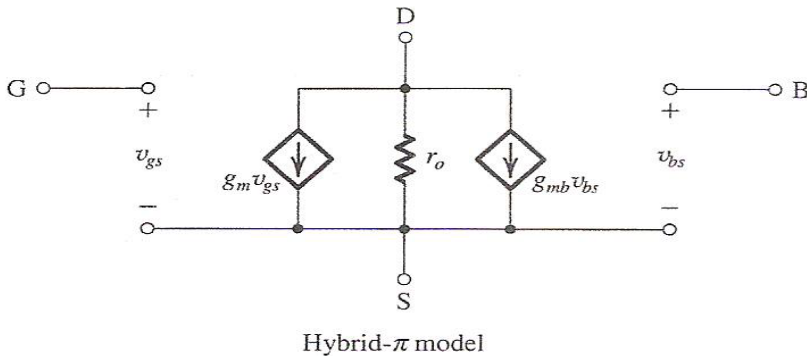
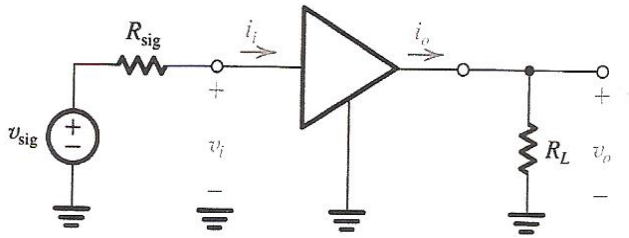


TABLE 4.3 Characteristic Parameters of Amplifiers

Circuit



Definitions

Input resistance with no load:

$$R_i \equiv \left. \frac{v_i}{i_i} \right|_{R_L = \infty}$$

Input resistance:

$$R_{in} \equiv \frac{v_i}{i_i}$$

Open-circuit voltage gain:

$$A_{vo} \equiv \left. \frac{v_o}{v_i} \right|_{R_L = \infty}$$

Voltage gain:

$$A_v \equiv \frac{v_o}{v_i}$$

Short-circuit current gain:

$$A_{is} \equiv \left. \frac{i_o}{i_i} \right|_{R_L = 0}$$

Current gain:

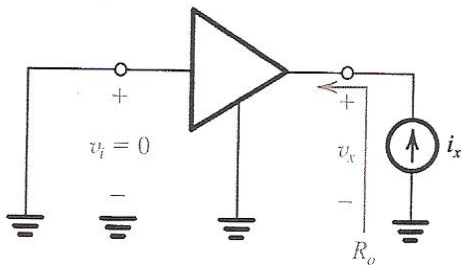
$$A_i \equiv \frac{i_o}{i_i}$$

Short-circuit transconductance:

$$G_m \equiv \left. \frac{i_o}{v_i} \right|_{R_L = 0}$$

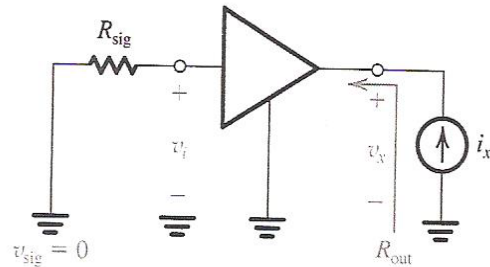
Output resistance of amplifier proper:

$$R_o \equiv \left. \frac{v_x}{i_x} \right|_{v_i = 0}$$



Output resistance:

$$R_{out} \equiv \left. \frac{v_x}{i_x} \right|_{v_{sig} = 0}$$



Open-circuit overall voltage gain:

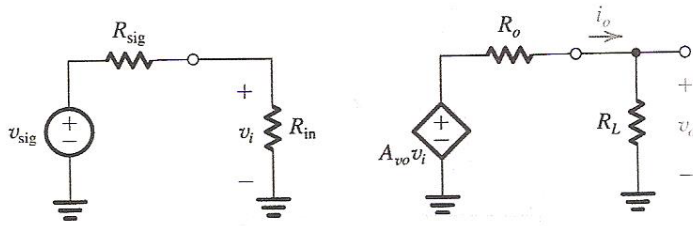
$$G_{vo} \equiv \left. \frac{v_o}{v_{sig}} \right|_{R_L = \infty}$$

Overall voltage gain:

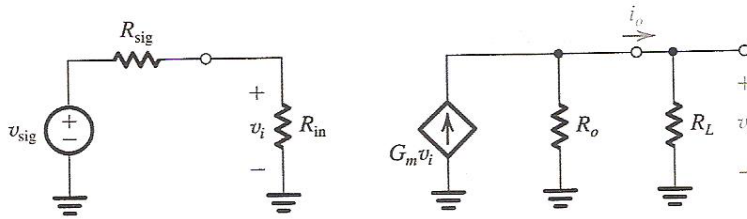
$$G_v \equiv \frac{v_o}{v_{sig}}$$

Equivalent Circuits

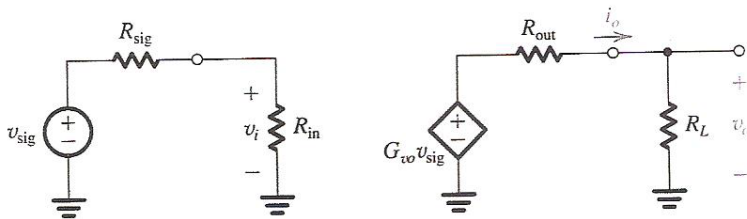
A:



B:



C:



Relationships

$$\frac{v_i}{v_{\text{sig}}} = \frac{R_{\text{in}}}{R_{\text{in}} + R_{\text{sig}}}$$

$$A_v = A_{vo} \frac{R_L}{R_L + R_o}$$

$$A_{vo} = G_m R_o$$

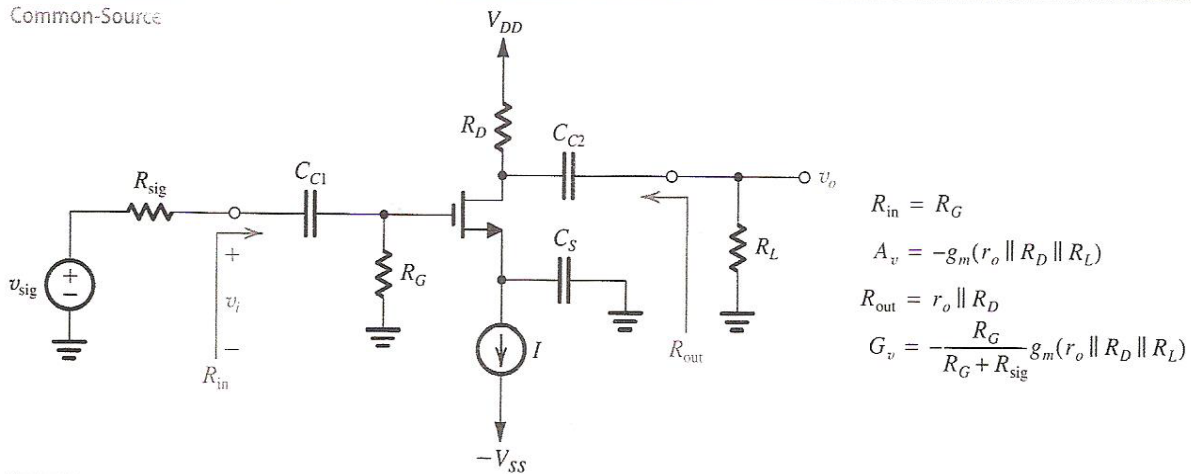
$$G_v = \frac{R_{\text{in}}}{R_{\text{in}} + R_{\text{sig}}} A_{vo} \frac{R_L}{R_L + R_o}$$

$$G_{vo} = \frac{R_i}{R_i + R_{\text{sig}}} A_{vo}$$

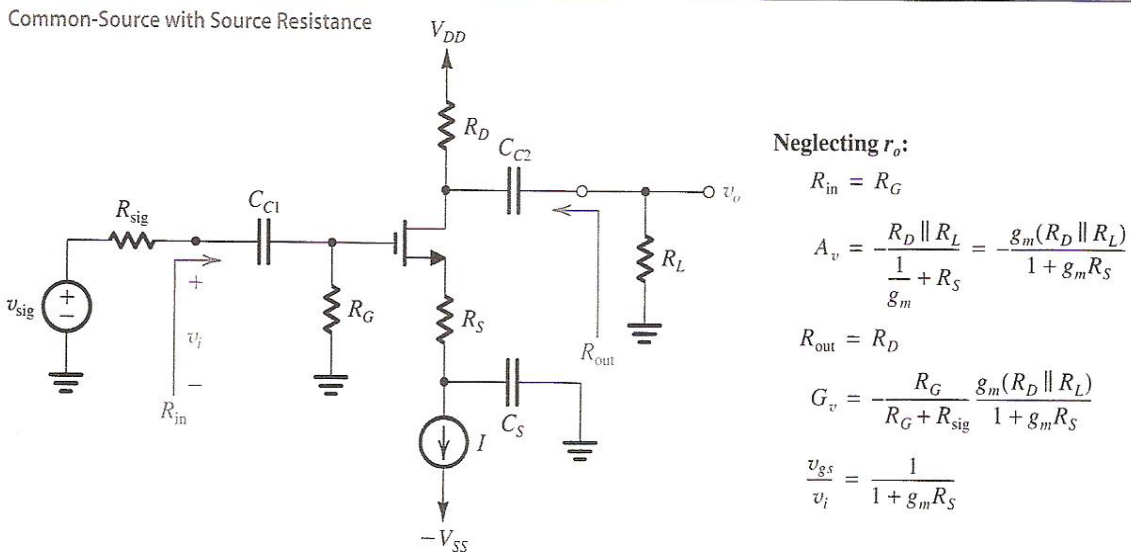
$$G_v = G_{vo} \frac{R_L}{R_L + R_{\text{out}}}$$

TABLE 4.4 Characteristics of Single-Stage Discrete MOS Amplifiers

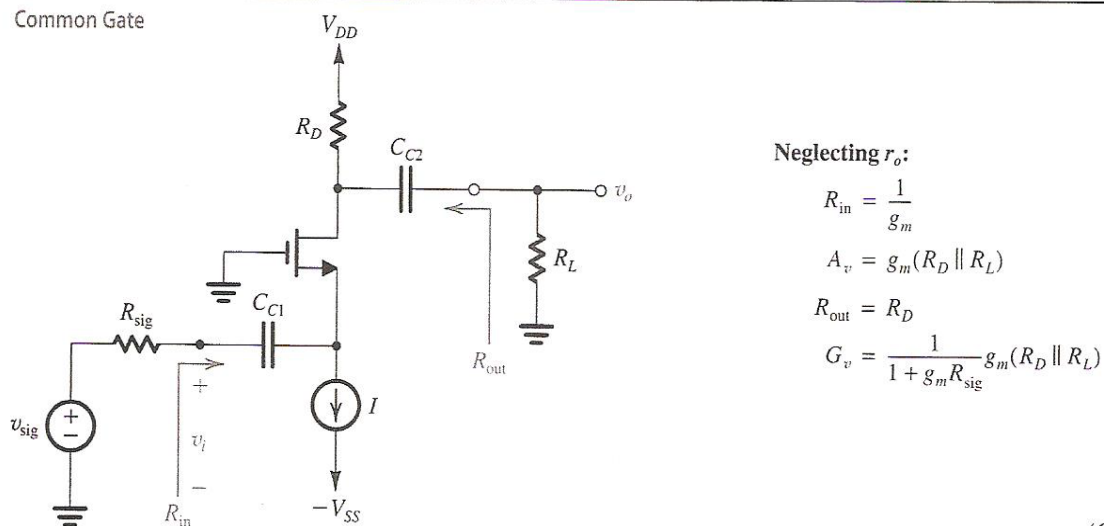
Common-Source



Common-Source with Source Resistance



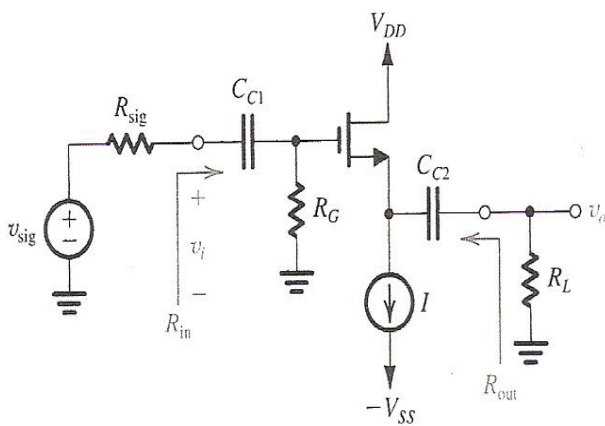
Common Gate



(Continued)

TABLE 4.4 (Continued)

Common-Drain or Source Follower



$$R_{in} = R_G$$

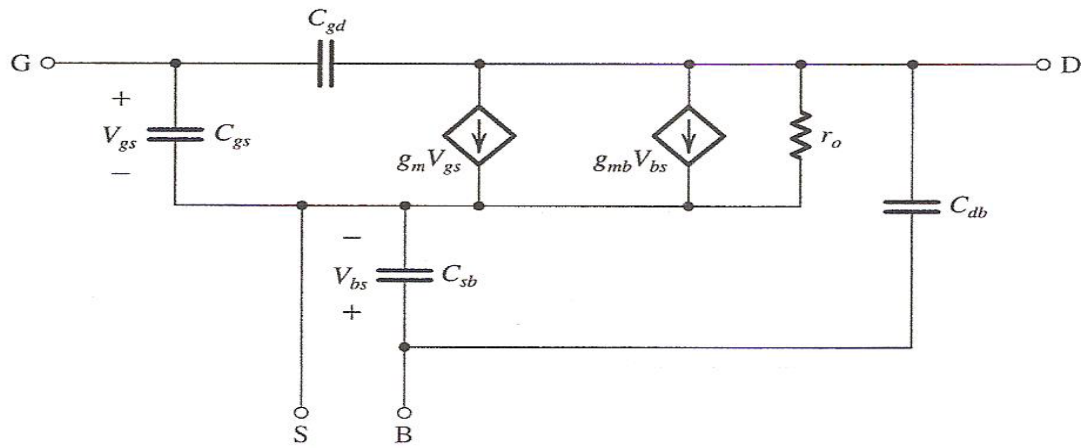
$$A_v = \frac{r_o \parallel R_L}{(r_o \parallel R_L) + \frac{1}{g_m}}$$

$$R_{out} = r_o \parallel \frac{1}{g_m} \cong \frac{1}{g_m}$$

$$G_v = \frac{R_G}{R_G + R_{sig}} \frac{r_o \parallel R_L}{(r_o \parallel R_L) + \frac{1}{g_m}}$$

TABLE 4.5 The MOSFET High-Frequency Model

Model



Model Parameters

$$g_m = \mu_n C_{ox} \frac{W}{L} V_{OV} = \sqrt{2\mu_n C_{ox} \frac{W}{L} I_D} = \frac{2I_D}{V_{OV}}$$

$$g_{mb} = \chi g_m = \frac{\gamma}{2\sqrt{2\phi_f + V_{SB}}} g_m$$

$$r_o = V_A / I_D$$

$$C_{gs} = \frac{2}{3} W L C_{ox} + W L_{ov} C_{ox}$$

$$C_{gd} = W L_{ov} C_{ox}$$

$$C_{sb} = \frac{C_{sb0}}{\sqrt{1 + \frac{V_{SB}}{V_0}}}$$

$$C_{db} = \frac{C_{db0}}{\sqrt{1 + \frac{V_{DB}}{V_0}}}$$

$$f_T = \frac{g_m}{2\pi(C_{gs} + C_{gd})}$$

TABLE 4.6 Summary of Important Characteristics of the CMOS Logic Inverter

Gate Output Resistance■ When v_O is low (current sinking) (Fig. 4.54):

$$r_{DSN} = 1 / \left[k'_n \left(\frac{W}{L} \right)_n (V_{DD} - V_{tn}) \right]$$

■ When v_O is high (current sourcing) (Fig. 4.55):

$$r_{DSP} = 1 / \left[k'_p \left(\frac{W}{L} \right)_p (V_{DD} - |V_{tp}|) \right]$$

Gate Threshold VoltagePoint on VTC at which $v_O = v_I$:

$$V_{th} = \frac{r(V_{DD} - |V_{tp}|) + V_{tn}}{1 + r}$$

where

$$r = \sqrt{\frac{k'_p (W/L)_p}{k'_n (W/L)_n}}$$

Switching Current and Power Dissipation (Fig. 4.58)

$$I_{\text{peak}} = \frac{1}{2} k'_n \left(\frac{W}{L} \right)_n \left(\frac{V_{DD}}{2} - V_{tn} \right)^2$$

$$P_D = f C V_{DD}^2$$

Noise Margins (Fig. 4.56)For matched devices, that is, $\mu_n \left(\frac{W}{L} \right)_n = \mu_p \left(\frac{W}{L} \right)_p$:

$$V_{th} = V_{DD}/2$$

$$V_{IL} = \frac{1}{8}(3V_{DD} + 2V_t)$$

$$V_{IH} = \frac{1}{8}(5V_{DD} - 2V_t)$$

$$NM_H = NM_L = \frac{1}{8}(3V_{DD} + 2V_t)$$

Propagation Delay (Fig. 4.57)For $V_t \cong 0.2V_{DD}$:

$$t_{PHL} \cong \frac{1.6C}{k'_n (W/L)_n V_{DD}}$$

$$t_{PLH} \cong \frac{1.6C}{k'_p (W/L)_p V_{DD}}$$
